SRAM

128K x 8 SRAM

WITH SINGLE CHIP ENABLE

AVAILABLE AS MILITARY SPECIFICATIONS

- SMD 5962-89598
- MIL-STD-883

FEATURES

- Ultra high speed: 15ns
- High speed: 20, 25, 35 and 45ns
- Battery Backup: 2V data retention
- Low power standby
- High-performance, low-power CMOS process
- Single +5V (±10%) power supply
- Easy memory expansion with $\overline{CE}$ and $\overline{OE}$ options
- All inputs and outputs are TTL compatible

OPTIONS — MARKING

- Timing

15ns access (contact factory)	-15 (New)
20ns access	-20
25ns access	-25
35ns access	-35
45ns access	-45
55ns access	-55*
70ns access	-70*

- Packages

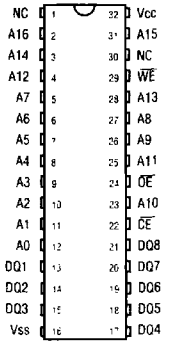
Ceramic DIP (400 mil)	C	No. 111
Ceramic DIP (600 mil)	CW	No. 112
Ceramic LCC	EC	No. 207
Ceramic LCC	ECA	No. 208
Ceramic Flat Pack	F	No. 303
Ceramic SOJ	DCJ	No. 501

- 2V data retention, low power standby — L
- Radiation Tolerant (EPI) — E

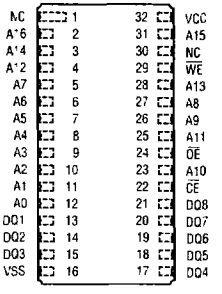
*Electrical characteristics identical to those provided for the 45ns access devices.

PIN ASSIGNMENT (Top View)

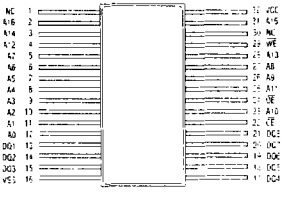
32-Pin DIP



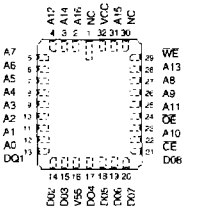
32-Pin LCC
32-Pin SOJ



32-Pin Flat Pack



32-Pin LCC



GENERAL DESCRIPTION

The Austin Semiconductor SRAM family employs high-speed, low-power CMOS designs using a four-transistor memory cell. Austin Semiconductor SRAMs are fabricated using double-layer metal, double-layer polysilicon technology.

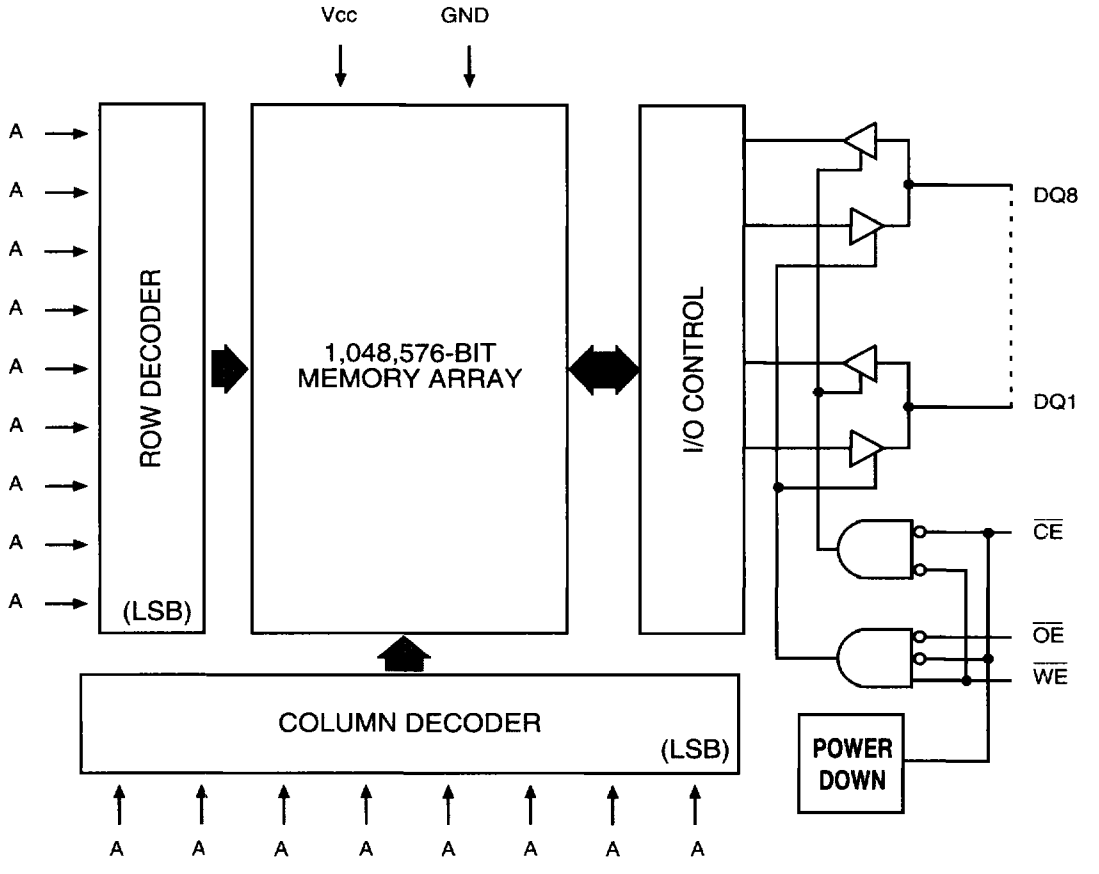
For flexibility in high-speed memory applications, Austin Semiconductor offers chip enable ($\overline{CE}$) and output enable ($\overline{OE}$) capability. These enhancements can place the outputs in High-Z for additional flexibility in system design.

Writing to these devices is accomplished when write enable ($\overline{WE}$) and $\overline{CE}$ inputs are both LOW. Reading is accomplished when $\overline{WE}$ remains HIGH while $\overline{CE}$ and $\overline{OE}$ go LOW. The devices offer a reduced power standby mode when disabled. This allows system designs to achieve low standby power requirements.

The "L" version provides an approximate 50 percent reduction in CMOS standby current (I_{SBC2}) over the standard version.

All devices operate from a single +5V power supply and all inputs and outputs are fully TTL compatible.

FUNCTIONAL BLOCK DIAGRAM



NOTE: The two least significant row address bits (A8 and A6) are encoded using gray code.

TRUTH TABLE

MODE	$\overline{OE}$	$\overline{CE}$	$\overline{WE}$	DQ	POWER
STANDBY	X	H	X	HIGH-Z	STANDBY
READ	L	L	H	Q	ACTIVE
READ	H	L	H	HIGH-Z	ACTIVE
WRITE	X	L	L	D	ACTIVE

ABSOLUTE MAXIMUM RATINGS*

Voltage on Any Input or DQ Relative to Vss .. -.5V to VCC+1v
Voltage on Vcc Supply Relative to Vss ..... -1V to +7V
Storage Temperature ..... -65°C to +150°C
Power Dissipation 1W
Short Circuit Output Current 20mA
Load Temperature (soldering temperature) ..... +260°C
Junction Temperature ..... +175°C

*Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

ELECTRICAL CHARACTERISTICS AND RECOMMENDED DC OPERATING CONDITIONS

($-55°C \le T_C \le 125°C$; $V_{CC} = 5.0V \pm 10\%$)

DESCRIPTION	CONDITIONS	SYMBOL	MIN	MAX	UNITS	NOTES
Input High (Logic 1) Voltage		V_{IH}	2.2	V_{CC}+.5	V	1
Input Low (Logic 0) Voltage		V_{IL}	-0.5	0.8	V	1, 2
Input Leakage Current	$0V \le V_{IN} \le V_{CC}$	I_{LI}	-5	5	µA	
Output Leakage Current	Output Disabled $0V \le V_{OUT} \le V_{CC}$	I_{LO}	-5	5	µA	
Output High Voltage	I_{OH} = -4.0mA	V_{OH}	2.4		V	1
Output Low Voltage	I_{OL} = 8.0mA	V_{OL}		0.4	V	1

			MAX						
DESCRIPTION	CONDITIONS	SYMBOL	-15	-20	-25	-35	-45	UNITS	NOTES
Power Supply Current: Operating	$\overline{CE} \le V_{IL}$; V_{CC} = MAX f = MAX = 1/ ^tRC (MIN) Output Open	I_{CC}	170	155	140	130	125	mA	3
Power Supply Current: Standby	$\overline{CE} \ge V_{IH}$; V_{CC} = MAX f = MAX = 1/ ^tRC (MIN) Output Open	I_{SBT1}	65	50	45	40	35	mA	
	$\overline{CE} \ge V_{IH}$, All Other Inputs $\le V_{IL}$ or $\ge V_{IH}$, V_{CC} = MAX f = 0 Hz	I_{SBT2}	25	25	25	25	25	mA	
	$\overline{CE} \ge V_{CC}$ -0.2V; V_{CC} = MAX $V_{IL} \le V_{SS}$ +0.2V $V_{IH} \ge V_{CC}$ -0.2V; f = 0 Hz	I_{SBC2}	10	10	10	10	10	mA	
	"L" Version Only	I_{SBC2}	5	5	5	5	5	mA	

CAPACITANCE

DESCRIPTION	CONDITIONS	SYMBOL	MIN	MAX	UNITS	NOTES
Input Capacitance ($\overline{OE}$, A2, A3, A10)	T_A = 25°C, f = 1MHz	C_I		10	pF	4
Output Capacitance (DQ1-DQ8)	V_{CC} = 5V	C_O		8	pF	4
Input Capacitance (All Other Inputs)		C_I		8	pF	4

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Note 5) (-55°C ≤ T_C ≤ 125°C; Vcc = 5V ± 10%)

DESCRIPTION		-15		-20		-25		-35		-45			
	SYM	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNITS	NOTES
READ Cycle													
READ cycle time	^tRC	15		20		25		35		45		ns	
Address access time	^tAA		15		20		25		35		45	ns	
Chip Enable access time	^tACE		15		20		25		35		45	ns	
Output hold from address change	^tOH	3		3		3		3		3		ns	
Chip Enable to output in Low-Z	^tLZCE	3		3		3		3		3		ns	4, 6, 7
Chip disable to output in High-Z	^tHZCE		6		8		10		15		15	ns	4, 6, 7
Chip Enable to power-up time	^tPU	0		0		0		0		0		ns	4
Chip disable to power-down time	^tPD		15		20		25		35		45	ns	4
Output Enable access time	^tAOE		6		7		8		12		12	ns	
Output Enable to output in Low-Z	^tLZOE	0		0		0		0		0		ns	
Output disable to output in High-Z	^tHZOE		5		7		9		12		12	ns	4, 6, 7
WRITE Cycle													
WRITE cycle time	^tWC	15		20		25		35		45		ns	
Chip Enable to end of write	^tCW	12		15		17		20		25		ns	
Address valid to end of write	^tAW	12		15		17		20		20		ns	
Address setup time	^tAS	0		0		0		0		0		ns	
Address hold from end of write	^tAH	1		1		1		1		1		ns	
WRITE pulse width	^tWP	12		15		17		20		20		ns	
Data setup time	^tDS	7		8		10		13		13		ns	
Data hold time	^tDH	0		0		0		0		0		ns	
Write disable to output in Low-Z	^tLZWE	3		3		3		3		3		ns	4, 6, 7
Write Enable to output in High-Z	^tHZWE	0	7	0	9	0	10	0	13	0	13	ns	4, 6, 7

AC TEST CONDITIONS

Input pulse levels	Vss to 3V
Input rise and fall times	5ns
Input timing reference levels	1.5V
Output reference levels	1.5V
Output load	See Figures 1 and 2

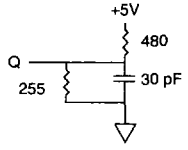


Fig. 1 OUTPUT LOAD EQUIVALENT

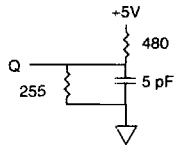


Fig. 2 OUTPUT LOAD EQUIVALENT

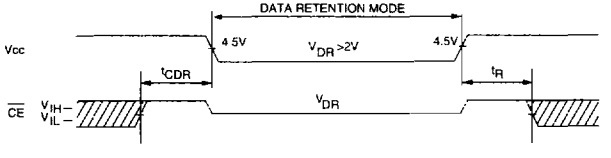
NOTES

1. All voltages referenced to Vss (GND).
2. -2V for pulse width < 20ns.
3. Icc is dependent on output loading and cycle rates. The specified value applies with the outputs unloaded, and $f = \frac{1}{{}^tRC\ (MIN)}$ Hz.
4. This parameter is guaranteed but not tested.
5. Test conditions as specified with the output loading as shown in Fig. 1 unless otherwise noted.
6. ^tLZCE, ^tLZOE, ^tLZWE, ^tHZCE, ^tHZOE and ^tHZWE are specified with CL = 5 pF as in Fig. 2. Transition is measured ± 200mV typical from steady state voltage, allowing for actual tester RC time constant.
7. At any given temperature and voltage condition, ^tHZCE is less than ^tLZCE and ^tHZWE is less than ^tLZWE, and ^tHZOE is less than ^tLZOE
8. $\overline{WE}$ is HIGH for READ cycle.
9. Device is continuously selected. Chip enable and output enable are held in their active state.
10. Address valid prior to or coincident with latest occurring chip enable.
11. ^tRC = READ cycle time.
12. Chip enable ($\overline{CE}$) and write enable ($\overline{WE}$) can initiate and terminate a WRITE cycle.

DATA RETENTION ELECTRICAL CHARACTERISTICS (L Version Only)

DESCRIPTION	CONDITIONS		SYMBOL	MIN	MAX	UNITS	NOTES
Vcc for Retention Data			VDR	2	—	V	
Data Retention Current	$\overline{CE}$ ≥ (Vcc - 0.2V) VIN ≥ (Vcc - 0.2V) or ≤ 0.2V	Vcc = 2V	ICCDR		1.0	mA	
		Vcc = 3V			1.5	mA	
Chip Deselect to Data Retention Time			^tCDR	0	—	ns	4
Operation Recovery Time			^tR	^tRC		ns	4, 11

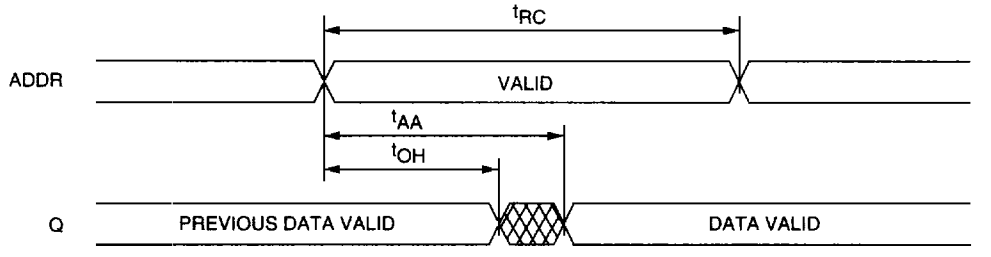
LOW Vcc DATA RETENTION WAVEFORM



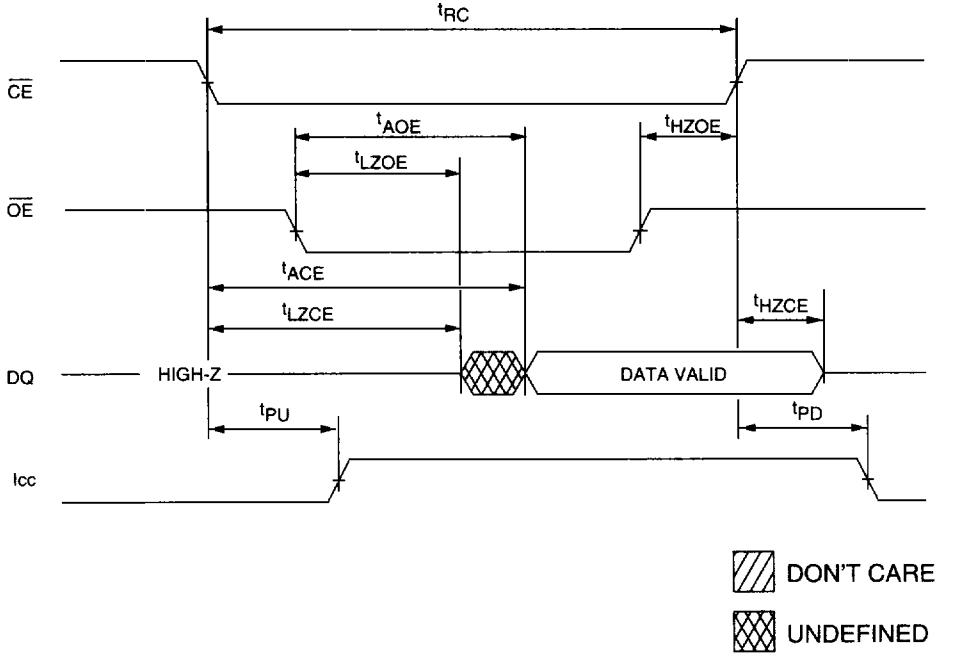
DON'T CARE

UNDEFINED

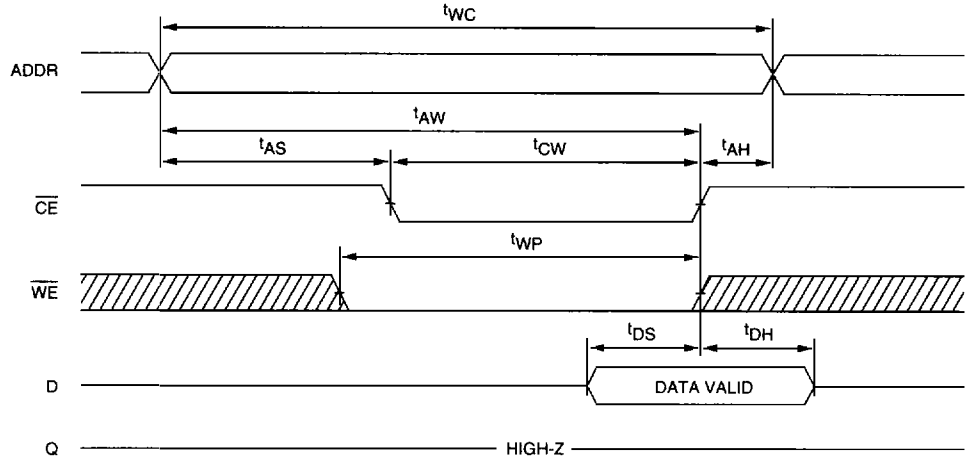
READ CYCLE NO. 1 [8, 9]



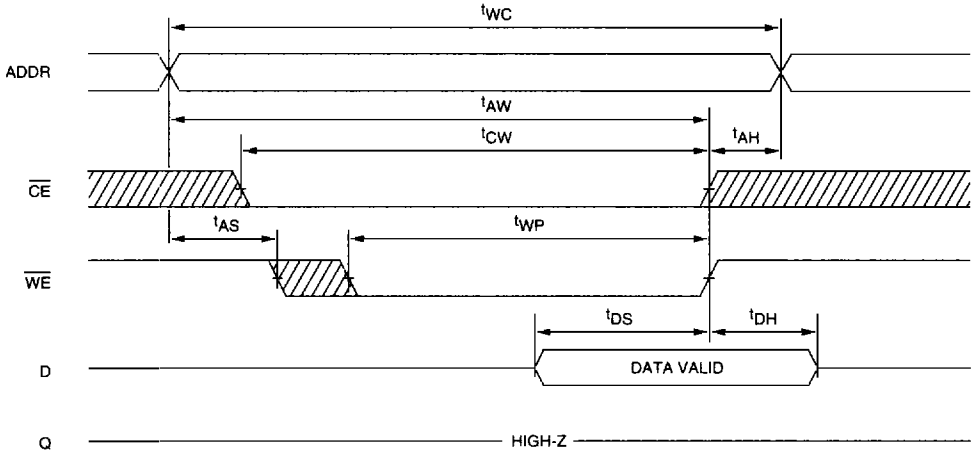
READ CYCLE NO. 2 [7, 8, 10]



WRITE CYCLE NO. 1 [12]
(Chip Enable Controlled)



WRITE CYCLE NO. 2 [7, 12]
(Write Enable Controlled)



DON'T CARE

UNDEFINED

NOTE: Output enable ($\overline{OE}$) is inactive (HIGH).

ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUPS (per Method 5005, Table I)
INTERIM ELECTRICAL (PRE-BURN-IN) TEST PARAMETERS (Method 5004)	2, 8A, 10
FINAL ELECTRICAL TEST PARAMETERS (Method 5004)	1*, 2, 3, 7*, 8, 9, 10, 11
GROUP A TEST REQUIREMENTS (Method 5005)	1, 2, 3, 4**, 7, 8, 9, 10, 11
GROUP C AND D END-POINT ELECTRICAL PARAMETERS (Method 5005)	1, 2, 3, 7, 8, 9, 10, 11

* PDA applies to subgroups 1 and 7.

** Subgroup 4 shall be measured only for initial qualification and after process or design changes, which may affect input or output capacitance.